## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Katsunori ICHIKI et al.

Serial Number: Not Yet Assigned

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For: BEAM SOURCE AND BEAM PROCESSING APPARATUS

## INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

March 11, 2004

Sir:

In compliance with 37 CFR 1.56, Applicant(s) call(s) to the attention of the Patent and Trademark Office the references listed on the attached PTO-1449.

A copy of each of the references is enclosed herewith.

In the event there are any fees due in connection with the filing of this paper, please charge Deposit Account No. <u>50-2866</u>.

Respectfully submitted,

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Enclosures: PTO-1449; References (10)

INFORMATION
DISCLOSURE
<b>STATEMENT</b>
PTO-1449

Attv. Docket No. 042183	Serial No. New Appln.
Applicant(s): Katsunori ICHIKI	et al.
Filing Date: March 11, 2004	Group Art Unit:

**U.S. PATENT DOCUMENTS** 

Examiner Initial		Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
	AA	4,158,589	Keller et al.	06/19/79			
	AB	5,827,435	Samukawa	10/27/98			
	AC	5,928,528	Kubota et al.	07/27/99			
	AD	6,217,703	Kitagawa	04/17/01			
	AE	6,331,701	Chen et al.	12/18/01			

## FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Translation (Yes or No)
AF	WO 01/06534	01/25/01	PCT ,	Abstract
AG	WO 02/078407	10/03/02	PCT	Abstract

## **OTHER DOCUMENTS**

AH	J.M.E. Harper et al., "Low Energy Ion Beam Etching", J. Electrochem. Soc: SOLID-STATE SCIENCE AND TECHNOLOGY, Vol.128, No. 5, May 1981, pp. 1077-1083.
AI	Harold R. Kaufman, "Technology of ion beam sources used in sputtering", J. Vac. Sci. Technol. 15(2), March/April 1978, pp. 272-276.
AJ	Shoji KITAMURA, "Ion Engine (Direct Current Discharge Type)", J. Vac. Soc. Jpn. Vol. 45, No. 4, 2002, pp. 329-335.

Examiner Date Considered